Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/532,169	ISHII ET AL.
Examiner	Art Unit
Amy R. Cohen	2859

SEARCHED			
Class	Cubalana	Dete	
Class	Subclass	Date	Examiner
116	200 201 206	6/23/2006	ARC
	207 216		
	217 219		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SE	CH NOTES EARCH STRATEGY)
	DATE	EXMR
Clss 116, Cohen	6/23/2006	ARC
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